

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/623,934	TAKAHASHI, NAOMASA	
Examiner	Art Unit	
TuyetLien (Lien) T. Tran	2179	

SEARCHED					
Class	Subclass	Date	Examiner		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Attached updated EAST search history	1/31/2008	т		
consulted with Ba Huynh, AU 2179	1/31/2008	ТТ		
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